

FDC699P

P-Channel 2.5V PowerTrench® MOSFET

General Description

This P-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V-12V).

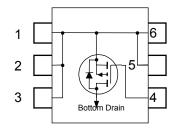
Applications

- Battery management
- Load Switch
- Battery protection

Features

- -7 A, -20 V $R_{DS(ON)} = 22 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 30 \text{ m}\Omega$ @ $V_{GS} = -2.5 \text{ V}$
- High performance trench technology for extremely low $R_{\ensuremath{\mathsf{DS}}(\ensuremath{\mathsf{ON}})}$
- · Fast switching speed
- FLMP SuperSOT-6 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	-7	А
	– Pulsed		-40	
P _D	Power Dissipation	(Note 1a)	2	W
		(Note 1b)	1.5	
T _J , T _{STG}	Operating and Storage Junction Temp	erature Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	60	°C/W
		(Note 1b)	111	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.5	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
.699	FDC699P	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	-1	ı	I	l	ı
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = -250 \mu\text{A}$	-20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$, Referenced to 25°C		-12		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μА
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.6	-0.9	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = $-250 \mu A$, Referenced to $25^{\circ}C$		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -7 \text{ A}$ $V_{GS} = -2.5 \text{ V}, I_D = -6 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -7 \text{ A}, T_J = 125^{\circ}\text{C}$		14 21 17	22 30 31	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -7 \text{ A}$		30		S
Dynamic	Characteristics		•	•		
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		2640		pF
Coss	Output Capacitance	f = 1.0 MHz		560		pF
C _{rss}	Reverse Transfer Capacitance	7		280		pF
R _G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		3.6		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$		16	28	ns
tr	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		11	19	ns
t _{d(off)}	Turn-Off Delay Time	7		75	120	ns
t _f	Turn-Off Fall Time	7		41	65	ns
Qg	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -7 \text{ A},$		27	38	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -5 \text{ V}$		5		nC
Q _{gd}	Gate-Drain Charge	1		7		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings	•	•		
Is	Maximum Continuous Drain-Source				-1.6	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \qquad I_S = -1.6 \text{ A (Note 2)}$		-0.7	-1.2	V
t _{rr}	Reverse Recovery Time	I _F = -7 A,		28		ns
Q _{rr}	Reverse Recovery Charge	$d_{iF}/d_{t} = 100 \text{ A/}\mu\text{s}$		14		nC

Notes: 1. $R_{0,lA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{0,lC}$ is guaranteed by design while $R_{0,lCA}$ is determined by the user's board design.



a) 60°C/W when mounted on a 1in² pad of 2 oz copper

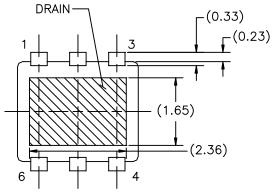


o) 111°C/W when mounted on a minimum pad of 2 oz copper

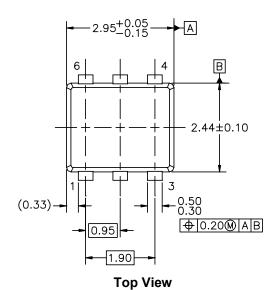
Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

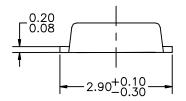
Dimensional Outline and Pad Layout

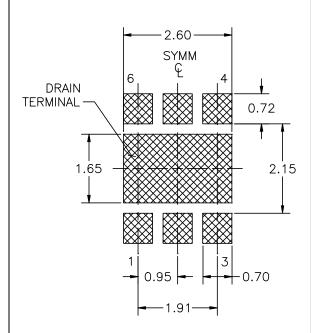


Bottom View



0.85 0.65 SEATING PLANE





Recommended Landing Pattern

Typical Characteristics

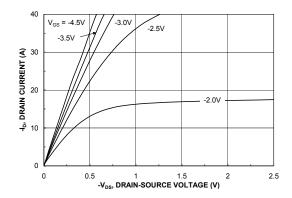


Figure 1. On-Region Characteristics.

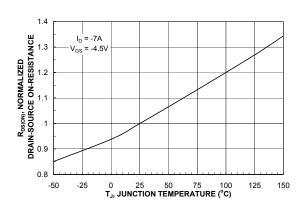


Figure 3. On-Resistance Variation withTemperature.

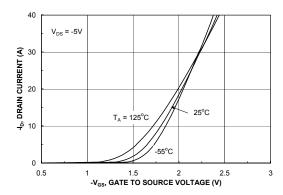


Figure 5. Transfer Characteristics.

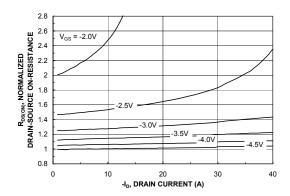


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

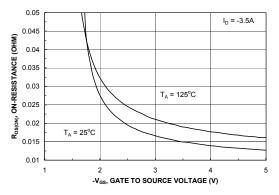


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

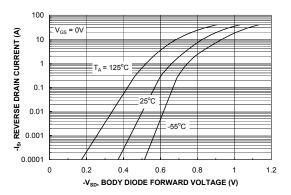
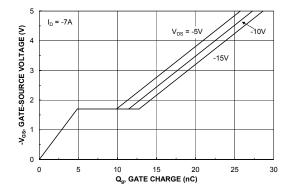


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



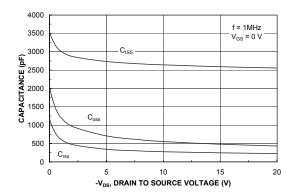


Figure 7. Gate Charge Characteristics.

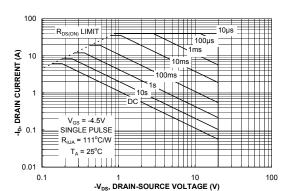


Figure 8. Capacitance Characteristics.

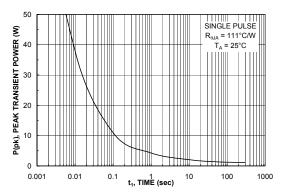


Figure 9. Maximum Safe Operating Area.



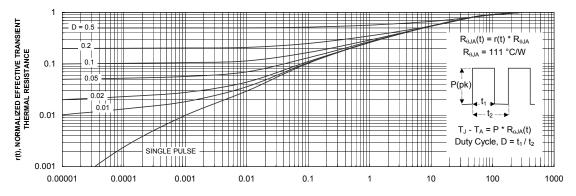


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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CROSSVOLT™	FRFET™	MicroPak™	QS™	SyncFET™
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